## What is claimed is:

- 1. An integrated circuit package comprising:
  - a substrate;
  - a die; and

a material having a Young's modulus of between about .1 megapascals and about 20 megapascals, at a solder reflow temperature, attaching the die to the substrate.

- 2. The integrated circuit package of claim 1, wherein the substrate comprises a ceramic.
- 3. The integrated circuit package of claim 1, wherein the die comprises one or more memory circuits.
- 4. The integrated circuit package of claim 1, wherein the die comprises one or more processor circuits.
- 5. The integrated circuit package of claim 1, wherein the die comprises one or more logic circuits.
- 6. The integrated circuit package of claim 1 wherein the die comprises one or more application specific integrated circuits.
- 7. The integrated circuit package of claim 1, wherein the material comprises a poly epoxide formed from one epoxide.
- 8. The integrated circuit package of claim 1, wherein the material comprises a poly epoxide formed from two or more epoxides.

- 9. The integrated circuit package of claim 1, wherein the material comprises a polyacrylate.
- 10. The integrated circuit package of claim 1, wherein the material comprises a polyolefin.
- 11. The integrated circuit package of claim 1, wherein the material comprises a polyimide.
- 12. The integrated circuit package of claim 1, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 13. The integrated circuit package of claim 1, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 14. The integrated circuit package of claim 1, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 15. The integrated circuit package of claim 1, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 16. The integrated circuit package of claim 1, wherein the material has a Shore A hardness of greater than about 70.
- 17. The integrated circuit package of claim 1, wherein the material has a Shore D hardness of greater than about 20.
- 18. An integrated circuit package comprising:a substrate;a die; and

a material having a coefficient of thermal expansion  $\alpha_2$  of less than about 400 (four-hundred) ppm/°C attaching the die to the substrate.

- 19. The integrated circuit package of claim 18, wherein the substrate comprises a single metal layer glass-epoxide.
- 20. The integrated circuit package of claim 18, wherein the die comprises one or more processor circuits.
- 21. The integrated circuit package of claim 18 wherein the die comprises one or more memory circuits.
- 22. The integrated circuit package of claim 18, wherein the die comprises one or more logic circuits.
- 23. The integrated circuit package of claim 18, wherein the die comprises one or more application specific integrated circuits.
- 24. The integrated circuit package of claim 18, wherein the material comprises a poly epoxide formed from one epoxide.
- 25. The integrated circuit package of claim 18, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 26. The integrated circuit package of claim 18, wherein the material comprises a polyacrylate.
- 27. The integrated circuit package of claim 18, wherein the material comprises a polyolefin.

- 28. The integrated circuit package of claim 18, wherein the material comprises a polyimide.
- 29. The integrated circuit package of claim 18, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 30. The integrated circuit package of claim 18, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 31. The integrated circuit package of claim 18, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 32. The integrated circuit package of claim 18, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 33. The integrated circuit package of claim 18, wherein the material has a Shore A hardness of greater than about 70.
- 34. The integrated circuit package of claim 18, wherein the material has a Shore D hardness of greater than about 20.
- 35. An integrated circuit package comprising:
  - a substrate;
  - a die; and
  - a rigid die attach material attaching the die to the substrate.
- 36. The integrated circuit package of claim 35, wherein the substrate comprises a printed circuit board.

- 37. The integrated circuit package of claim 35, wherein the die comprises a communication circuit.
- 38. The integrated circuit package of claim 35, wherein the die comprises one or more memory circuits.
- 39. The integrated circuit package of claim 35, wherein the die comprises one or more processor circuits.
- 40. The integrated circuit package of claim 35, wherein the die comprises one or more logic circuits.
- 41. The integrated circuit package of claim 35, wherein the die comprises one or more application specific integrated circuits.
- 42. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a poly epoxide formed from one epoxide.
- 43. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a poly epoxide formed from two or more epoxides.
- 44. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a polyacrylate.
- 45. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a polyolefin.
- 46. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a polyimide.

- 47. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 48. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 49. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a mixture of a poly epoxide and a polyimide.
- 50. The integrated circuit package of claim 35, wherein the rigid die attach material comprises a copolymer of a poly epoxide and a polyimide.
- 51. The integrated circuit package of claim 35, wherein the rigid die attach material has a Shore A hardness of greater than about 70.
- 52. The integrated circuit package of claim 35, wherein the rigid die attach material has a Shore D hardness of greater than about 20.
- 53. An electronic system package comprising:
  - a circuit board;
  - a die; and
- a material having a Young's modulus of between about .1 megapascals and about 20 megapascals at a solder reflow temperature of between about 200 degrees Centigrade and 280 degrees Centigrade, the material attaching the die to the circuit board.
- 54. The electronic system package of claim 53, wherein the circuit board comprises a flexible circuit board.

- 55. The electronic system package of claim 53, wherein the die comprises an integrated circuit fabricated on silicon.
- 56. The electronic system package of claim 53, wherein the die comprises one or more memory circuits.
- 57. The electronic system package of claim 53, wherein the die comprises one or more processor circuits.
- 58. The electronic system package of claim 53, wherein the die comprises one or more logic circuits.
- 59. The electronic system package of claim 53, wherein the die comprises one or more application specific integrated circuits.
- 60. The electronic system package of claim 53, wherein the material comprises a poly epoxide formed from one epoxide.
- 61. The electronic system package of claim 53, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 62. The electronic system package of claim 53, wherein the material comprises a polyacrylate.
- 63. The electronic system package of claim 53, wherein the material comprises a polyolefin.
- 64. The electronic system package of claim 53, wherein the material comprises a polyimide.

- 65. The electronic system package of claim 53, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 66. The electronic system package of claim 53, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 67. The electronic system package of claim 53, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 68. The electronic system package of claim 53, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 69. The electronic system package of claim 53, wherein the material has a Shore A hardness of greater than about 70.
- 70. The electronic system package of claim 53, wherein the material has a Shore D hardness of greater than about 20.
- 71. An electronic system package comprising:
  - a circuit board;
  - a die; and
- a material having a coefficient of thermal expansion  $\alpha_2$  of less than about 400 (four-hundred) ppm/°C at a solder reflow temperature of about between about 200 degrees Centigrade and about 280 degrees Centigrade, the material attaching the die to the circuit board.
- 72. The electronic system package of claim 71, wherein the circuit board comprises a multi-metal layer circuit board.

- 73. The electronic system package of claim 71, wherein the die comprises gallium arsenide.
- 74. The electronic system package of claim 71, wherein the material comprises one or more polyimides.
- 75. The electronic system package of claim 71, wherein the die comprises one or more memory circuits.
- 76. The electronic system package of claim 71, wherein the die comprises one or more processor circuits.
- 77. The electronic system package of claim 71, wherein the die comprises one or more logic circuits.
- 78. The electronic system package of claim 71, wherein the die comprises one or more application specific integrated circuits.
- 79. The electronic system package of claim 71, wherein the material comprises a poly epoxide formed from one epoxide.
- 80. The electronic system package of claim 71, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 81. The electronic system package of claim 71, wherein the material comprises a polyacrylate.
- 82. The electronic system package of claim 71, wherein the material comprises a polyolefin.

- 83. The electronic system package of claim 71, wherein the material comprises a polyimide.
- 84. The electronic system package of claim 71, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 85. The electronic system package of claim 71, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 86. The electronic system package of claim 71, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 87. The electronic system package of claim 71, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 88. The electronic system package of claim 71, wherein the material has a Shore A hardness of greater than about 70.
- 89. The electronic system package of claim 71, wherein the material has a Shore D hardness of greater than about 20.
- 90. An electronic system package comprising:
  - a circuit board;
  - a die; and
  - a rigid die attach material attaching the die to the substrate.
- 91. The electronic system package of claim 90, wherein the circuit board comprises a multi-metal layer circuit board.

- 92. The electronic system package of claim 90, wherein the die comprises germanium.
- 93. The electronic system package of claim 90, wherein the die comprises one or more memory circuits.
- 94. The electronic system package of claim 90, wherein the die comprises one or more processor circuits.
- 95. The electronic system package of claim 90, wherein the die comprises one or more logic circuits.
- 96. The electronic system package of claim 90, wherein the die comprises one or more application specific integrated circuits.
- 97. The electronic system package of claim 90, wherein the rigid die attach material comprises a poly epoxide formed from one epoxide.
- 98. The electronic system package of claim 90, wherein the rigid die attach material comprises a poly epoxide formed from two or more epoxides.
- 99. The electronic system package of claim 90, wherein the rigid die attach material comprises a polyacrylate.
- 100. The electronic system package of claim 90, wherein the rigid die attach material comprises a polyolefin.
- 101. The electronic system package of claim 90, wherein the rigid die attach material comprises a polyimide.

- 102. The electronic system package of claim 90, wherein the rigid die attach material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 103. The electronic system package of claim 90, wherein the rigid die attach material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 104. The electronic system package of claim 90, wherein the rigid die attach material comprises a mixture of a poly epoxide and a polyimide.
- 105. The electronic system package of claim 90, wherein the rigid die attach material comprises a copolymer of a poly epoxide and a polyimide.
- 106. The electronic system package of claim 90, wherein the rigid die attach material has a Shore A hardness of greater than about 70.
- 107. The electronic system package of claim 90, wherein the rigid die attach material has a Shore D hardness of greater than about 20.
- 108. An integrated circuit package comprising:
  - a ceramic substrate;
  - a die; and
- a material having a Young's modulus of between about .1 and about 20, at a solder reflow temperature, attaching the die to the substrate.
- 109. The integrated circuit package of claim 108, wherein the ceramic substrate comprises a multi-metal layer ceramic substrate.

- 110. The integrated circuit package of claim 108, wherein the die comprises a communication circuit fabricated on a semiconductor.
- 111. The integrated circuit package of claim 108, wherein the die comprises one or more memory circuits.
- 112. The integrated circuit package of claim 108, wherein the die comprises one or more processor circuits.
- 113. The integrated circuit package of claim 108, wherein the die comprises one or more logic circuits.
- 114. The integrated circuit package of claim 108, wherein the die comprises one or more application specific integrated circuits.
- 115. The integrated circuit package of claim 108, wherein the material comprises one or more epoxides, poly epoxides, copolymers of epoxides, or mixtures thereof.
- 116. The integrated circuit package of claim 108, wherein the material comprises a poly epoxide formed from one epoxide.
- 117. The integrated circuit package of claim 108, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 118. The integrated circuit package of claim 108, wherein the material comprises a polyacrylate.
- 119. The integrated circuit package of claim 108, wherein the material comprises a polyolefin.

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- 120. The integrated circuit package of claim 108, wherein the material comprises a polyimide.
- 121. The integrated circuit package of claim 108, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 122. The integrated circuit package of claim 108, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 123. The integrated circuit package of claim 108, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 124. The integrated circuit package of claim 108, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 125. The integrated circuit package of claim 108, wherein the material has a Shore A hardness of greater than about 70.
- 126. The integrated circuit package of claim 108, wherein the material has a Shore D hardness of greater than about 20.
- 127. An integrated circuit package comprising:
  - a ceramic substrate;
  - a die; and
- a material having a low coefficient of thermal expansion attaching the die to the substrate.
- 128. The integrated circuit package of claim 127, wherein the ceramic substrate comprises a single layer ceramic substrate.

- 129. The integrated circuit package of claim 127, wherein the die comprises a processor fabricated on a semiconductor.
- 130. The integrated circuit package of claim 127, wherein the die comprises one or more memory circuits.
- 131. The integrated circuit package of claim 127, wherein the die comprises one or more logic circuits.
- 132. The integrated circuit package of claim 127, wherein the die comprises one or more application specific integrated circuits.
- 133. The integrated circuit package of claim 127, wherein the material comprises one or more polyolefins.
- 134. The integrated circuit package of claim 127, wherein the material has a Shore A hardness of greater than about 70.
- 135. The integrated circuit package of claim 127, wherein the material has a Shore D hardness of greater than about 20.
- 136. An integrated circuit package comprising:
  - a ceramic substrate;
  - a die; and
  - a rigid die attach material attaching the die to the substrate.
- 137. The integrated circuit package of claim 136, wherein the ceramic substrate comprises a multilayered ceramic substrate.

- 138. The integrated circuit package of claim 136, wherein the die comprises germanium.
- 139. The integrated circuit package of claim 136, wherein the die comprises one or more memory circuits.
- 140. The integrated circuit package of claim 136, wherein the die comprises one or more processor circuits.
- 141. The integrated circuit package of claim 136, wherein the die comprises one or more logic circuits.
- 142. The integrated circuit package of claim 136, wherein the die comprises one or more application specific integrated circuits.
- 143. The integrated circuit package of claim 136, wherein the rigid die attach material comprises one or more epoxides, poly epoxides, copolymers of epoxides, or mixtures thereof.
- 144. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a poly epoxide formed from one epoxide.
- 145. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a poly epoxide formed from two or more epoxides.
- 146. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a polyacrylate.
- 147. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a polyolefin.

- 148. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a polyimide.
- 149. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 150. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 151. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a mixture of a poly epoxide and a polyimide.
- 152. The integrated circuit package of claim 136, wherein the rigid die attach material comprises a copolymer of a poly epoxide and a polyimide.
- 153. The integrated circuit package of claim 136, wherein the rigid die attach material has a Shore A hardness of greater than about 70.
- 154. The integrated circuit package of claim 136, wherein the rigid die attach material has a Shore D hardness of greater than about 20.
- 155. A memory circuit package comprising:
  - a substrate;
  - a die; and
- a material having a Young's modulus of between about .1 and about 20, at a solder reflow temperature, attaching the die to the substrate.

- 156. The memory circuit package of claim 155, wherein the substrate comprises a glass-epoxide.
- 157. The memory circuit package of claim 155, wherein the die comprises one or more memory cells.
- 158. The memory circuit package of claim 155, wherein the die comprises one or more processor circuits.
- 159. The memory circuit package of claim 155, wherein the die comprises one or more logic circuits.
- 160. The memory circuit package of claim 155, wherein the die comprises one or more application specific integrated circuits.
- 161. The memory circuit package of claim 155, wherein the material comprises one or more epoxides, poly epoxides, copolymers of epoxides, or mixtures thereof.
- 162. The memory circuit package of claim 155, wherein the material comprises a poly epoxide formed from one epoxide.
- 163. The memory circuit package of claim 155, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 164. The memory circuit package of claim 155, wherein the material comprises a polyacrylate.
- 165. The memory circuit package of claim 155, wherein the material comprises a polyolefin.

- 166. The memory circuit package of claim 155, wherein the material comprises a polyimide.
- 167. The memory circuit package of claim 155, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 168. The memory circuit package of claim 155, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 169. The memory circuit package of claim 5, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 170. The memory circuit package of claim 155, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 171. The memory circuit package of claim 155, wherein the material has a Shore A hardness of greater than about 70.
- 172. The memory circuit package of claim 155, wherein the material has a Shore D hardness of greater than about 20.
- 173. An memory circuit package comprising:
  - a substrate;
  - a die; and
- a material having a low coefficient of thermal expansion attaching the die to the substrate.
- 174. The memory circuit package of claim 173, wherein the substrate comprises a printed circuit board.

- 175. The memory circuit package of claim 173, wherein the die comprises one or more dynamic random access memory circuits fabricated on a semiconductor.
- 176. The memory circuit package of claim 173, wherein the material comprises one or more polyimides.
- 177. The memory circuit package of claim 173, wherein the material comprises a poly epoxide formed from one epoxide.
- 178. The memory circuit package of claim 173, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 179. The memory circuit package of claim 173, wherein the material comprises a polyacrylate.
- 180. The memory circuit package of claim 173, wherein the material comprises a polyolefin.
- 181. The memory circuit package of claim 173, wherein the material comprises a polyimide.
- 182. The memory circuit package of claim 173, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 183. The memory circuit package of claim 173, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 184. The memory circuit package of claim 173, wherein the material comprises a mixture of a poly epoxide and a polyimide.

- 185. The memory circuit package of claim 173, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 186. The memory circuit package of claim 173, wherein the material has a Shore A hardness of greater than about 70.
- 187. The memory circuit package of claim 173, wherein the material has a Shore D hardness of greater than about 20.
- 188. A memory circuit package comprising:
  - a substrate;
  - a die; and
  - a rigid die attach material attaching the die to the substrate.
- 189. The memory circuit package of claim 188, wherein the die comprises one or more static random access memory cells.
- 190. The memory circuit package of claim 188, wherein the rigid die attach material comprises one or more epoxides, poly epoxides, copolymers of epoxides, or mixtures thereof.
- 191. The memory circuit package of claim 188, wherein the rigid die attach material comprises a poly epoxide formed from one epoxide.
- 192. The memory circuit package of claim 188, wherein the rigid die attach material comprises a poly epoxide formed from two or more epoxides.
- 193. The memory circuit package of claim 188, wherein the rigid die attach material comprises a polyacrylate.

- 194. The memory circuit package of claim 188, wherein the rigid die attach material comprises a polyolefin.
- 195. The memory circuit package of claim 188, wherein the rigid die attach material comprises a polyimide.
- 196. The memory circuit package of claim 188, wherein the rigid die attach material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 197. The memory circuit package of claim 188, wherein the rigid die attach material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 198. The memory circuit package of claim 188, wherein the rigid die attach material comprises a mixture of a poly epoxide and a polyimide.
- 199. The memory circuit package of claim 188, wherein the rigid die attach material comprises a copolymer of a poly epoxide and a polyimide.
- 200. The memory circuit package of claim 188, wherein the rigid die attach material has a Shore A hardness of greater than about 70.
- 201. The memory circuit package of claim 188, wherein the rigid die attach material has a Shore D hardness of greater than about 20.
- 202. A communication system package comprising:a circuit board;a die; and

a material having a Young's modulus of between about .1 megapascals and about 20 megapascals, at a solder reflow temperature, attaching the die to the circuit board.

- 203. The communication system package of claim 202, wherein the die comprises a communication circuit.
- 204. The communication system package of claim 202, wherein the material comprises one or more epoxides, poly epoxides, copolymers of epoxides, or mixtures thereof.
- 205. The communication system package of claim 202, wherein the material comprises a poly epoxide formed from one epoxide.
- 206. The communication system package of claim 202, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 207. The communication system package of claim 202, wherein the material comprises a polyacrylate.
- 208. The communication system package of claim 202, wherein the material comprises a polyolefin.
- 209. The communication system package of claim 202, wherein the material comprises a polyimide.
- 210. The communication system package of claim 202, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 211. The communication system package of claim 202, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.

- 212. The communication system package of claim 202, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 213. The communication system package of claim 202, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 214. The communication system package of claim 202, wherein the material has a Shore A hardness of greater than about 70.
- 215. The communication system package of claim 202, wherein the material has a Shore D hardness of greater than about 20.
- 216. A communication system package comprising:
  - a substrate;
  - a die; and
- a material having a low coefficient of thermal expansion attaching the die to the substrate.
- 217. The communication system package of claim 216, wherein the substrate comprises a multilayered substrate.
- 218. The communication system package of claim 216, wherein the die comprises a communication circuit fabricated on a semiconductor.
- 219. The communication system package of claim 216, wherein the material comprises one or more acrylates, polyacrylates, or mixtures thereof.
- 220. The communication system package of claim 216, wherein the material comprises a poly epoxide formed from one epoxide.

- 221. The communication system package of claim 216, wherein the material comprises a poly epoxide formed from two or more epoxides.
- 222. The communication system package of claim 216, wherein the material comprises a polyacrylate.
- 223. The communication system package of claim 216, wherein the material comprises a polyolefin.
- 224. The communication system package of claim 216, wherein the material comprises a polyimide.
- 225. The communication system package of claim 216, wherein the material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 226. The communication system package of claim 216, wherein the material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 227. The communication system package of claim 216, wherein the material comprises a mixture of a poly epoxide and a polyimide.
- 228. The communication system package of claim 216, wherein the material comprises a copolymer of a poly epoxide and a polyimide.
- 229. The communication system package of claim 216, wherein the material has a Shore A hardness of greater than about 70.
- 230. The communication system package of claim 216, wherein the material has a Shore D hardness of greater than about 20.

- 231. A communication system package comprising:
  - a ceramic substrate;
  - a die; and
  - a rigid die attach material attaching the die to the substrate.
- 232. The communication system package of claim 231, wherein the ceramic substrate comprises a multilayered ceramic substrate.
- 233. The communication system package of claim 231, wherein the die comprises a transmitter fabricated on silicon.
- 234. The communication system package of claim 231, wherein the die comprises one or more memory circuits.
- 235. The communication system package of claim 231, wherein the die comprises one or more processor circuits.
- 236. The communication system package of claim 231, wherein the die comprises one or more logic circuits.
- 237. The communication system package of claim 231, wherein the die comprises one or more application specific integrated circuits.
- 238. The communication system package of claim 231, wherein the rigid die attach material comprises an epoxide.
- 239. The communication system package of claim 231, wherein the rigid die attach material comprises a poly epoxide formed from one epoxide.

- 240. The communication system package of claim 231, wherein the rigid die attach material comprises a poly epoxide formed from two or more epoxides.
- 241. The communication system package of claim 231, wherein the rigid die attach material comprises a polyacrylate.
- 242. The communication system package of claim 231, wherein the rigid die attach material comprises a polyolefin.
- 243. The communication system package of claim 231, wherein the rigid die attach material comprises a polyimide.
- 244. The communication system package of claim 231, wherein the rigid die attach material comprises a mixture of at least two of a poly epoxide, polyacrylate, polyimide, and polyolefin.
- 245. The communication system package of claim 231, wherein the rigid die attach material comprises a copolymer of at least two of a poly epoxide, a polyacrylate, polyimide, and polyolefin.
- 246. The communication system package of claim 231, wherein the rigid die attach material comprises a mixture of a poly epoxide and a polyimide.
- 247. The communication system package of claim 231, wherein the rigid die attach material comprises a copolymer of a poly epoxide and a polyimide.
- 248. The communication system package of claim 231, wherein the rigid die attach material has a Shore A hardness of greater than about 70.

- 249. The communication system package of claim 231, wherein the rigid die attach material has a Shore D hardness of greater than about 20.
- 250. A method of packaging a die, the method comprising: positioning a die on a substrate;

providing a die attach material having a Young's modulus of between about .1 megapascal and 20 megapascals, at a solder reflow temperature, to secure the die to the substrate; and

reflowing one or more solder balls in contact with the substrate and a board.

251. A method of packaging a die, the method comprising:

positioning a die on a substrate; and

providing a die attach material having a coefficient of thermal expansion of less
than about 400 (four-hundred) to secure the die to the substrate.